Sample Results Summary Sheet
Please return this form to the Curator for each allocated Sample

Sample ID: RB-QD04-0037-01
PI: Masayuki Uesugi

Type and date of analysis performed:
FIB sectioning (Jul. 15, 2013)

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)
N/A

Contaminant phases identified: (Al, SUS, carbon particles, etc.)
N/A

Sample handling: (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)
Pressed on In plate (3mm diameter and 0.3mm thick) by Sapphire glass
Sectioned by Focused Ion Beam (FIB) (2 ultra-thin sections were extracted).

State of sample pre-analysis:
N2 hold.

State of sample post-analysis:
RB-QD04-0037-01:pressed on In plate, partially sectioned by FIB, damaged by Ga beam, N2 hold in sample holder
RB-QD04-0037-01-01: UTS by FIB
RB-QD04-0037-01-02: UTS by FIB

Analysis data Notes: (summary of the attached analysis data and/or images)

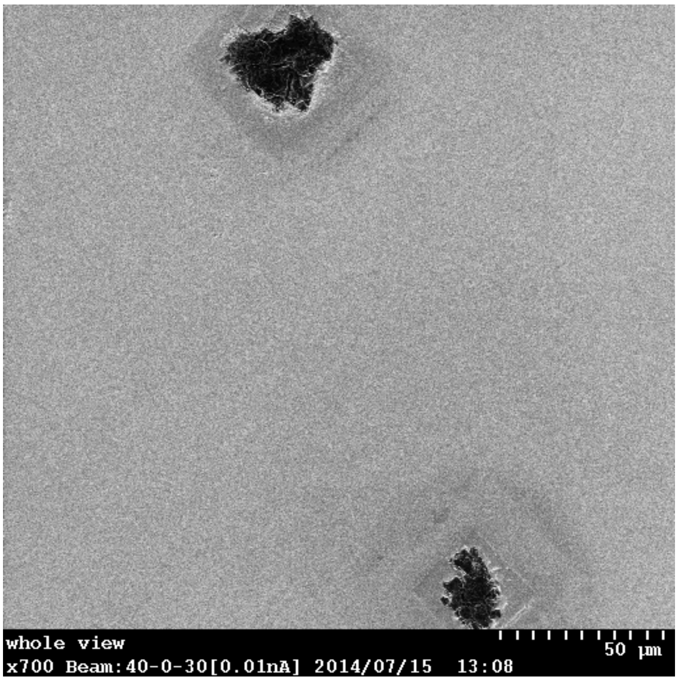

Fig.1 Scanning Ion microscope (SIM) imageof RB-QD04-0037-01 after pressing on In plate. Broken into two pieces. The lower one was fabricated by FIB.

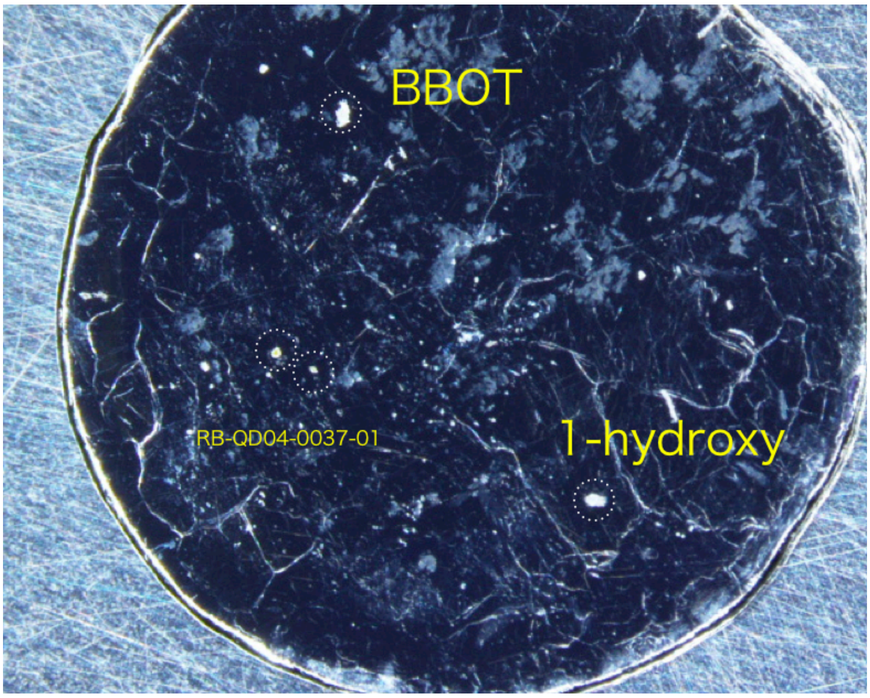

Fig. 2 Whole view of In plate. Standards for NanoSIMS analysis were also pressed on the In plate fixed on a half-inch stab holder.

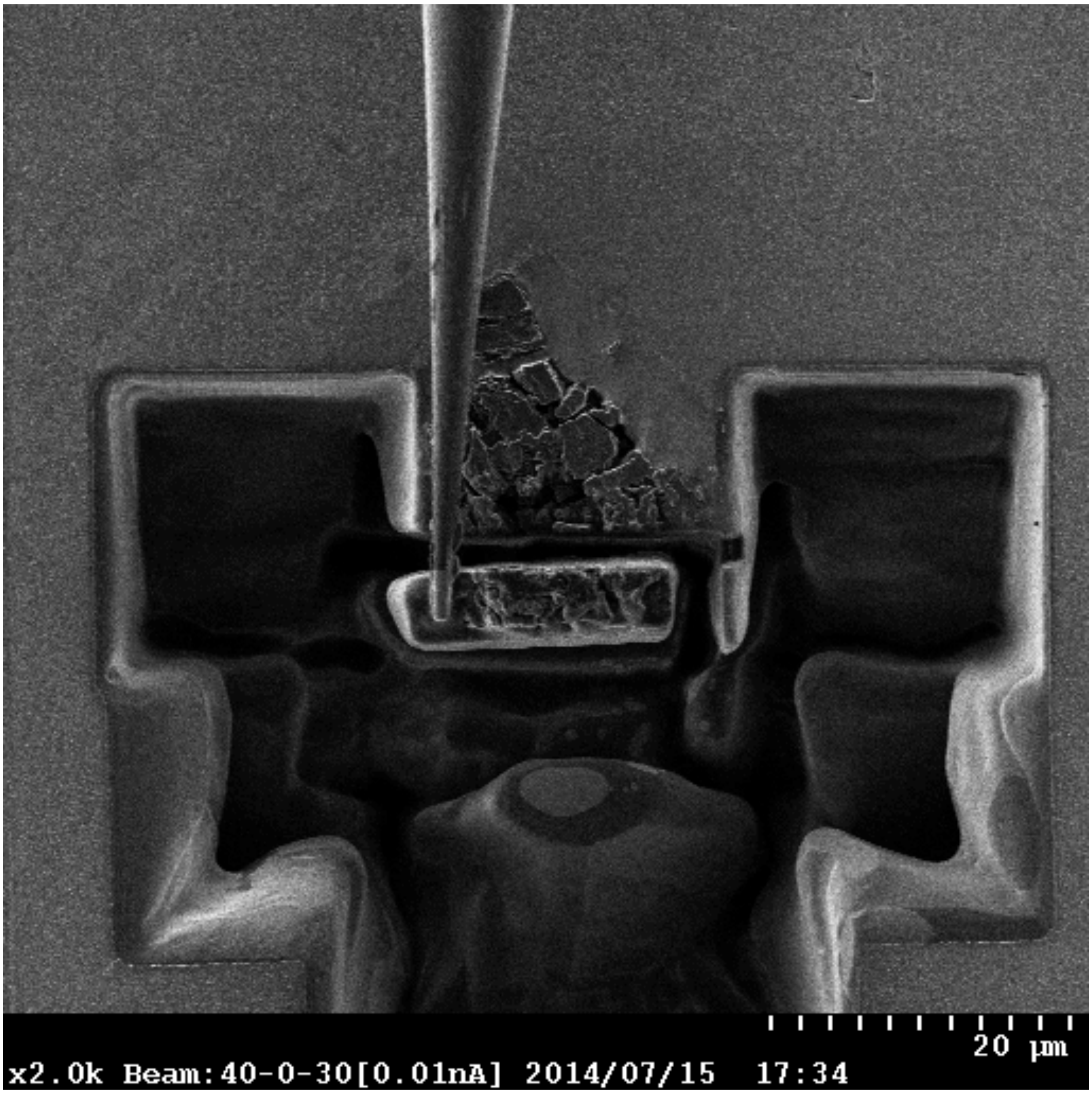

Fig. 3 SIM image of extraction of RB-QD04-0037-01-02 by FIB fabrication (final condition of RB-QD04-0037-01).